

# FTD09N20R

# N-Channel MOSFET

# **Applications:**

- Adaptor
- Charger
- .SMPS

## Features:

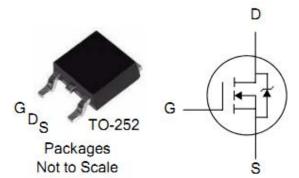
- RoHS Compliant
- . Low ON Resistance
- . Low Gate Charge
- Peak Current vs Pulse Width Curve
- Inductive Switching Curves

## **Ordering Information**

PART NUMBER	PACKAGE	BRAND
FTD09N20R	TO-252	IPS

<u> </u>		
V <sub>DSS</sub>	R <sub>DS(ON)</sub> (Typ.)	Ι <sub>D</sub>
200V	0.24Ω	9A

(Pb) Lead Free Package and Finish



#### Absolute Maximum Ratings

 $T_{C}=25^{\circ}C$  unless otherwise specified

Symbol	Parameter	FTD09N20R	Units	
V <sub>DSS</sub>	Drain-to-Source Voltage	200	V	
I <sub>D</sub>	Continuous Drain Current	9	А	
	Continuous Drain Current $T_C = 100^{\circ}C$	5.4	Α	
I <sub>DM</sub>	Pulsed Drain Current (NOTE *1)	36	Α	
Р	Power Dissipation	75	W	
P <sub>D</sub>	Derating Factor above 25°C	0.6	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	±30	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy(NOTE *2)	200	mJ	
dv/dt	Peak Diode Recovery dv/dt(NOTE *3)	5	V/ns	
TL	Maximum Temperature for Soldering	300		
$T_{\rm J}$ and $T_{\rm STG}$	Operating Junction and Storage Temperature Range	150,-55 to150	°C	

#### **Thermal Resistance**

Symbol	Parameter	Max.	Units	Test Conditions
R <sub>eJC</sub>	Junction-to-Case	1.67		Water cooled heatsink, $P_{D}$ adjusted for a
κ <sub>θ</sub> jc	JUIICIIOII-IO-Case	1.07	°C <b>/W</b>	peak junction temperature of +150℃.
R <sub>0JA</sub>	Junction-to-Ambient	100		1 cubic foot chamber, free air.



Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	200			V	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1	μA	V <sub>DS</sub> =200V, V <sub>GS</sub> =0V T,∣=25℃
				100		V <sub>DS</sub> =160V, V <sub>GS</sub> =0V T <sub>J</sub> =125℃
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			+100	nA	V <sub>GS</sub> =+30V
	Gate-to-Source Reverse Leakage			-100		V <sub>GS</sub> = -30V

## **OFF Characteristics** $T_C=25^{\circ}C$ unless otherwise specified

#### **ON Characteristics** $T_J=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
R <sub>DS(ON)</sub>	StaticDrain-to-Source On-Resistance		0.24	0.28	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =4.5A
$V_{GS(TH)}$	Gate Threshold Voltage	2		4	V	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250µA
<b>g</b> <sub>fs</sub>	Forward Transconductance		5		S	V <sub>DS</sub> =15V, I <sub>D</sub> =4.5A
Pulse width $\leq$ 300µs; duty cycle $\leq$ 2%						

#### Source-Drain Diode Characteristics

Tc=25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
I <sub>S</sub>	Continuous Source Current (Body Diode)			9	А	T 05°0	
I <sub>SM</sub>	Maximum Pulsed Current (Body Diode)			36	А	T <sub>C</sub> =25℃	
V <sub>SD</sub>	Diode Forward Voltage			1.5	V	I <sub>SD</sub> =9A, V <sub>GS</sub> =0V	
Pulse width $\leq$ 300 $\mu$ s; duty cycle $\leq$ 2%							

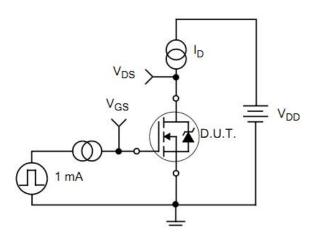
Notes:

- \*1. Repetitive rating; pulse width limited by maximum junction temperature.
- \*2. L=10mH, I\_D=7.1A, Start T\_J=25 $^\circ\!\mathrm{C}$
- \*3. I<sub>SD</sub> =9A,di/dt ≤100A/us,V<sub>DD</sub>≤BV<sub>DS</sub>, Start T<sub>J</sub>=25 $^\circ\!\!\mathbb{C}$



# **Test Circuits and Waveforms**

Figure 14. Gate Charge Test Circuit



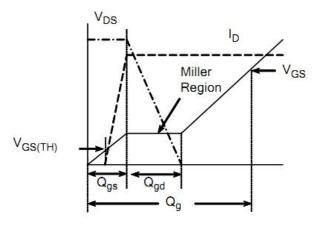
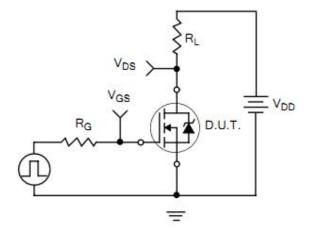
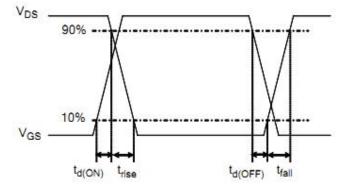


Figure 15. Gate Charge Waveforms

Figure 16. Resistive Switching Test Circuit

Figure 17. Resistive Switching Waveforms







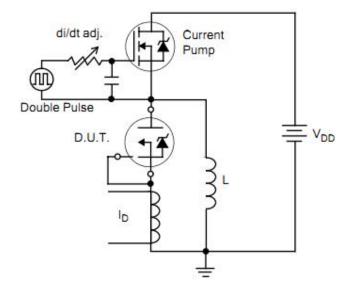


Figure 18. Diode Reverse Recovery Test Circuit

Figure 19. Diode Reverse Recovery Waveform

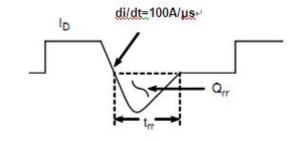
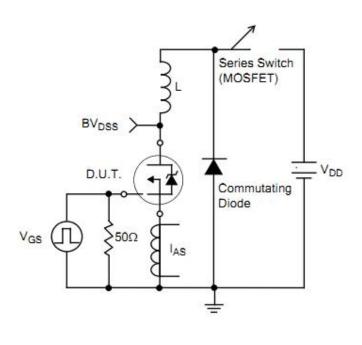
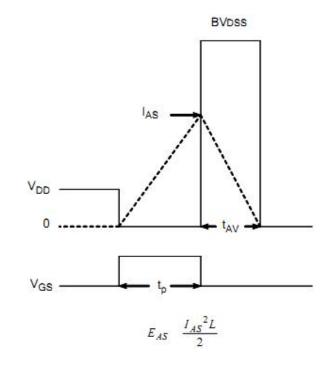


Figure20.Unclamped Inductive Switching Test Circuit

Figure21.Unclamped Inductive Switching Waveform







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